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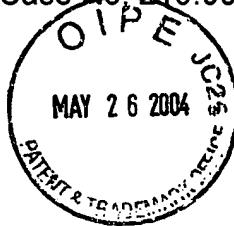
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Case No. 219.003-US)

In the Application of: Yamada

Serial No: 09/865,528

Filed: May 29, 2001

Title: Semiconductor Device Test Method and
Semiconductor Device Tester



) Group
) Art Unit: 2829
) Before
) Examiner: V. Nguyen

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

FEE TRANSMITTAL

Dear Sir:

Transmitted herewith is an **Information Disclosure Statement** (1 page + Form PTO-1449 (1 sheet) and references cited therein.

The fee has been calculated as shown below:

CLAIMS AS AMENDED						
	Claims Remaining	Highest Number Previously Paid	Extra	Rate		Amount
				Large	Small	
Number of Claims In (in excess of 20)	0	0	0	\$18.00	\$9.00	-0-
Independent Claims (in excess of 3)	0	0	0	\$84.00	\$42.00	-0-
Extension Fee: a) One Month				\$110.00	\$55.00	-0-
Filing of Information Disclosure Statement (37 C.F.R. §1.17(p)):						\$180.00
TOTAL FEE DUE:						\$180.00

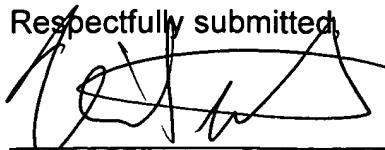
Method of Payment:

[XX] A check payable to the Commissioner of Patents and Trademarks, in the amount of \$180.00 is enclosed as payment of the Total Fee.

[] Please charge my Deposit Acc. 50-0763 in the amount of \$ _____ to cover the above fees. A duplicate copy of this sheet is enclosed.

[XX] The Commissioner is hereby authorized to charge any fees that may be required, or credit any overpayment to Deposit Acc. 50-0763. A duplicate copy of this sheet is enclosed.

Respectfully submitted,


Neil Steinberg, Reg. No. 34,735
Telephone No. (650) 968-8079

Date: May 24, 2004



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(219.003-US)

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Alexandria, VA 22313-1450

Certificate of Mailing under 37 CFR 1.8

I hereby certify that the attached: (1) Information Disclosure Statement (1 page + Modified PTO-1449 (1 sheet) and References cited therein); (2) Fee Transmittal (1 page + 1 copy thereof); (3) Check (\$180.00) are being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to:

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

on May 24, 2004.

Signature

Print Name of Person Signing Certificate

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) Art Unit: **2829**
)
) Before
) Examiner: **V. Nguyen**
)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Submitted herewith is one (1) sheet of a modified Form PTO-1449. A copy of each document cited on the attached Form PTO-1449 is also submitted.

It is respectfully requested that the Examiner make his/her consideration of these documents formally of record with the initial Office Action.

Respectfully submitted,



Neil A. Steinberg
Reg. No. 34,735
650-968-8079

Date: May 24, 2004

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Sheet 1 of 3

PTO-1449 (Modified) U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO.	SERIAL NUMBER
	219.003-US	09/865,528
	APPLICANT(S) Yamada	
FILING DATE	GROUP ART UNIT	
May 29, 2001	2829	

U. S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,989,919	11/1999	Aoki			
	6,466,315	10/2002	Karpol et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	